

Form PTO-1449

Information Disclosure Citation

Attorney Docket	TI-35189	Application No.	10/723,472
Applicant	Feng CHEN	Examiner	WAMSLEY
Application Filing Date	November 26, 2003	Group Art Unit	2819

U.S. Patent Documents

Examiner Initials	Cls.	Patent Number	Date	Name	Class	Sub-Class	Filing Date
	A						
	B						
	C						
	D						
	E						

Foreign Patent Documents

Examiner Initials	Cls.	Document Number	Date	Country	Name	Class	Sub-Class	Trans-lation
	F							Yes No
	G							Yes No
	H							Yes No

Other Documents (Including Author, Title, Date, Pertinent Pages, etc.)

<i>Chen</i>	I	J. Fattaruso, S. Kiriaki, M. de Wit, and G. Warwar, "Self-Calibration Techniques for a Second-Order Multibit Sigma-Delta Modulator," <i>IEEE Journal of Solid-State Circuits</i> , Vol. 28, No. 12, pp. 1216-1223, December 1993.
	J	F. Chen and B. Leung, "A High Resolution Multibit Sigma-Delta Modulator with Individual Level Averaging," <i>1994 Symposium on VLSI Circuits Digest of Technical Papers</i> , pp. 101-102, 1994. <i>No merit</i>
	K	R. Baird and T. Fiez, "Linearity Enhancement of Multibit Delta Sigma A/D and D/A Converters Using Data Weighted Averaging," <i>IEEE Transactions on Circuits and System—II: Analog and Digital Signal Processing</i> , Vol. 42, No. 12, pp. 753-762, December 1995.
<i>Chen</i>	L	I. Fujimori, L. Longo, A. Hairapetian, K. Seiyama, S. Kosic, J. Cao and S. Chan, "A 90 dB SNR, 2.5 MHz Output Rate ADC using Cascaded Multibit Delta Sigma Modulation at 8x Oversampling Ratio," <i>2000 IEEE International Solid-State Circuits Conference (ISSCC)</i> , (WA 20.3) (2000). <i>No merit</i>

Examiner Signature

Christopher Wamsley

Date Considered

03/01/2005

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.